

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		<div style="border: 1px solid black; border-radius: 50%; padding: 10px; display: inline-block;">             OIPE 3618              NOV 24 2003              PATENT &amp; TRADEMARK OFFICE           </div>		DOCKET NO: 006726 USA/ETCH/CONE/JB		APPLICATION NO.: 10/646,943	
INFORMATION DISCLOSURE STATEMENT IN AN APPLICATION				APPLICANT: Barnes et al.		FILING DATE: 8/21/2003	
GROUP ART UNIT: Unknown							

U.S. PATENT DOCUMENTS												
EXAMINER INITIAL	DOCUMENT NUMBER							DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
SN	4	6	1	1	9	1	9	09/16/1986	Brooks, Jr. et al.			
	4	8	4	2	6	8	3	06/27/1989	Cheng et al.			
	4	8	6	7	8	4	1	09/19/1989	Loewenstein et al.			
	4	9	2	4	8	0	7	05/15/1990	Nakayama et al.			
	4	9	3	1	1	3	5	06/05/1990	Horiuchi et al.			
	4	9	3	5	6	6	1	06/19/1990	Heinecke et al.			
	4	9	5	3	9	8	2	09/04/1990	Ebbing et al.			
	4	9	6	0	4	8	8	10/02/1990	Law et al.			
	4	9	8	0	2	0	4	12/25/1990	Fuji et al.			
SN	5	0	7	0	8	1	4	12/10/1991	Whiffin et al.			

FOREIGN PATENT DOCUMENTS													
	DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
	YES	NO											
SN	3	2	8	1	7	8	0	12/12/1991	Japan			Abstract	
↑	6	1	3	2	2	2	3	05/13/1994	Japan			Abstract	
	5	0	4	7	7	0	7	02/26/1993	Japan			Abstract	
	6	1	2	4	1	9	30	10/28/1986	Japan			Abstract	
	3	2	8	1	7	8	0	12/12/1991	Japan			Abstract	
	1	2	4	8	5	2	0	10/04/1989	Japan			Abstract	
	1	8	9	9	2	8		09/27/1985	Japan			Abstract	
	6	1	2	4	9	0	9	05/06/1994	Japan			Abstract	
↓	0	8	1	0	6	3	0	12/03/1997	EP			X	
	0	7	2	1	2	1		04/02/1987	Japan			X	
SN	9	6	1	9	8	2	5	06/27/1996	PCT			x	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)	
SN	Zhang et al., "Automated Process Control of Within-Wafer and Wafer-to-Wafer Uniformity in Oxide CMP", CMP-MIC, March 2002
SN	NANOMETRICS Applications Note, "Optical Measurement of Critical Dimensions", August 2001
EXAMINER	DATE CONSIDERED 07/19/04

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		NOV 2 8 2003 PATENT & TRADEMARK OFFICE		DOCKET NO: 006726 USA/ETCH/CONE/JB		APPLICATION NO.: 10/646,943	
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U.S. PATENT DOCUMENTS												
EXAMINER INITIAL	DOCUMENT NUMBER							DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
SN	5	0	8	4	1	2	6	01/28/1992	McKee			
	5	2	4	4	5	0	1	09/14/1993	Nakayama et al.			
	5	2	5	2	1	7	8	10/12/1993	Moslehi			
	5	2	6	9	8	4	7	12/14/1993	Anderson et al.			
	5	3	7	2	6	7	3	12/13/1994	Stager et al.			
	5	3	8	9	1	9	7	02/14/1995	Ishimaru			
	5	4	0	5	4	8	8	04/11/1995	Dimitrelis et al.			
	5	4	2	7	8	7	8	06/27/1995	Corliss			
SW	5	4	5	3	1	2	4	09/26/1995	Moslehi et al.			
	5	5	2	2	9	3	4	06/04/1996	Suzuki et al.			

FOREIGN PATENT DOCUMENTS													
	DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
	YES	NO											
SN	0	7	0	2	3	9	2	03/20/1996	EP			X	
↑	9	9	5	7	7	4	7	11/11/1999	PCT			X	
↓	0	4	1	0	4	4	2	07/26/1990	EP			X	
SN	9	8	0	0	5	7	6	01/08/1998	PCT			X	


  

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)	

EXAMINER <i>Sandhu</i>	DATE CONSIDERED <i>7/19/04</i>
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EXAMINER INITIAL	DOCUMENT NUMBER							DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
EN	5	5	3	2	1	9	0	07/02/1996	Goodyear et al.			
	5	5	5	6	5	2	1	09/17/1996	Ghanbari			
	5	5	8	9	0	0	2	12/31/1996	Su			
	5	5	9	2	3	5	8	01/07/1997	Shamouilian et al.			
	5	6	1	4	0	2	6	03/25/1997	Williams			
	5	6	2	4	4	9	8	04/29/1997	Lee et al.			
	5	6	5	3	8	0	8	08/05/1997	MacLeish et al.			
	5	6	8	3	5	1	7	11/04/1997	Shan			
	5	6	8	3	5	4	8	11/04/1997	Hartig et al.			
EN	5	7	2	0	8	1	8	02/24/1998	Donde et al.			

FOREIGN PATENT DOCUMENTS													
	DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
												YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)	

EXAMINER <i>Sanyal</i>	DATE CONSIDERED <i>7/19/04</i>
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EXAMINER INITIAL	DOCUMENT NUMBER							DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
SN	5	7	6	7	6	2	8	06/16/1998	Keller et al.			
	5	7	7	2	7	7	1	06/30/1998	Li et al.			
	5	8	1	4	1	5	3	09/29/1998	Ishikawa			
	5	8	1	9	4	3	4	10/13/1998	Herchen et al.			
	5	8	8	2	4	1	7	03/16/1999	Van de Ven et al.			
	5	9	1	0	0	1	1	06/08/1999	Cruse			
	5	9	1	3	1	0	2	06/15/1999	Yang			
	5	9	6	3	3	2	9	10/05/1999	Conrad et al.			
SN	5	9	7	6	3	0	8	11/02/1999	Fairbairn et al.			
	5	9	8	0	6	8	6	11/09/1999	Goto			

FOREIGN PATENT DOCUMENTS													
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												YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)	

EXAMINER: <span style="font-family: cursive; font-size: 1.2em;">Sanghyun</span>	DATE CONSIDERED: <span style="font-family: cursive; font-size: 1.2em;">7/19/04</span>
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<b>U.S. PATENT DOCUMENTS</b>												
EXAMINER INITIAL	DOCUMENT NUMBER							DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE
SN	5	9	9	7	9	5	0	12/07/1999	Telford et al.			
	6	0	0	1	2	6	7	12/14/1999	Os et al.			
	6	0	9	0	2	1	0	07/18/2000	Ballance et al.			
	6	0	1	2	4	7	8	01/11/2000	Park			
	6	1	0	8	1	8	9	08/22/2000	Weldon et al.			
	6	1	1	3	9	8	4	09/05/2000	MacLeish et al.			
	6	1	5	0	6	6	4	11/21/2000	Su			
	6	1	7	0	4	2	8	01/09/2001	Redeker et al.			
	6	1	7	9	9	2	4	01/30/2001	Zhao et al.			
SN	6	1	8	5	8	3	9	02/13/2001	Kholodenko et al.			

<b>FOREIGN PATENT DOCUMENTS</b>												
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION							
					YES	NO						

<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>	

EXAMINER <span style="font-family: cursive;">Sargis M</span>	DATE CONSIDERED <span style="font-family: cursive;">7/19/04</span>
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10/646,943INFORMATION DISCLOSURE STATEMENT  
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Unknown

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EXAMINER INITIAL	DOCUMENT NUMBER							DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
SN	6	3	0	3	5	0	7	10/16/2001	Wang et al.			
	6	3	3	3	2	7	2	12/25/2001	McMillan et al.			
	6	3	5	0	3	9	0	02/26/2002	Liu et al.			
	6	3	8	8	2	5	3	05/14/2002	Su			
	6	4	0	3	4	9	1	06/11/2002	Liu et al.			
	0	1	8	8	4	1	7	12/12/2002	Levy et al.			
SN	0	0	1	1	7	8	6	01/16/2003	Levy et al.			

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	DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
												YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)


EXAMINER

Sang Hoon

DATE CONSIDERED

7/19/04

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